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Ion Implantation Technology. 2002. Proceedings of the 14th International

Conference on , 22-27 Sept. 2002

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1 Precise beam incidence angle control on the VIISta 810HP

Weeman, J.; Olson, J.; Guo, B.N.; Jeong, U.; Li, G.C.; Mehta, S.;

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Carelli, P.; Foglietti, V.; Leoni, R.;

Magnetics, IEEE Transactions on , Volume: 23 , Issue: 2 , Mar 1987 Pages:1087 - 1089

IEEE JNI [PDF Full-Text (560 KB)]

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# 3 100 GHz wafer probes based on photoconductive sampling

Feuer, M.D.; Shunk, S.C.; Smith, P.R.; Nuss, M.C.; Law, N.H.; Photonics Technology Letters, IEEE , Volume: 5 , Issue: 3 , March 1993 Pages:361 - 364

[Abstract] [PDF Full-Text (356 KB)] refe JNL

4 Production use of an integrated automatic defect classification (ADC) system operating in a laser confocal/white light imaging defect review

Advanced Semiconductor Manufacturing Conference and Workshop, 1996. ASMC 96 Proceedings. IEEE/SEMI 1996, 12-14 Nov. 1996 Li, J.; McIntyre, M.; Lee, K.; Worster, B.; Pages:107 - 111

[Abstract] [PDF Full-Text (452 KB)] IEEE CNF

 $_5$  A (100) silicon stress test chip with optimized piezoresistive sensor

rosettes

Electronic Components and Technology Conference, 1994. Proceedings., 44th, 1-4 Jaeger, R.C.; Suhling, J.C.; Anderson, A.A.; May 1994

Pages:741 - 749

[Abstract] [PDF Full-Text (664 KB)] IEEE CNF

6 Broadband optoelectronic wafer probing

High Speed Semiconductor Devices and Circuits, 1993. Proceedings., IEEE/Cornell Feuer, M.D.; Shunk, S.C.; Smith, P.R.; Law, H.H.; Burrus, C.A.; Nuss, M.C.;

Conference on Advanced Concepts in , 2-4 Aug. 1993

Pages:485 - 493

[Abstract] [PDF Full-Text (556 KB)] IEEE CNF

7 Emissivity correcting pyrometer for temperature measurement in low Fordham, M.J.; Gansman, R.F.; Sorrell, F.Y.; pressure chemical vapor deposition

University/Government/Industry Microelectronics Symposium, 1993., Proceedings of the Tenth Biennial, 18-19 May 1993

Pages:223 - 228

[Abstract] [PDF Full-Text (424 KB)] IEEE CNF

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Booth, J.C.; Beall, J.A.; DeGroot, D.C.; Rudman, D.A.; Ono, R.H.; Miller, J.R.;

Applied Superconductivity, IEEE Transactions on , Volume: 7 , Issue: 2 , June 1997 Chen, M.L.; Hong, S.H.; Ma, Q.Y.;

Pages:2780 - 2783

## IEEE JNL [PDF Full-Text (488 KB)] Abstract

2 Phase-sensitive vision technique for high accuracy position measurement of moving targets

Instrumentation and Measurement, IEEE Transactions on , Volume: 49 , Issue: Sandoz, P.; Ravassard, J.C.; Dembele, S.; Janex, A.; 4, Aug. 2000

Print Formst

Pages:867 - 872

IEEE JNL [PDF Full-Text (152 KB)] Abstracti 3 Real-time estimation of patterned wafer parameters using in situ

Galarza, C.G.; Khargonekar, P.P.; Terry, F.L., Jr.;

spectroscopic ellipsometry

Control Applications, 1999. Proceedings of the 1999 IEEE International Conference

on , Volume: 1 , 22-27 Aug. 1999 Pages:773 - 778 vol. 1

IEEE CNF [PDF Full-Text (480 KB)] [Abstract] 4 How good is your calibration? A post-mortem examination and recalibration

Aguilera, J.; Fisher, B.;

Instrumentation and Measurement Technology Conference, 1990. IMTC-90.

Conference Record., 7th IEEE, 13-15 Feb. 1990

Pages:195

IEEE CNF [PDF Full-Text (28 KB)] [Abstract] 5 Hybrid optical-electrical overlay test structure [for CMOS]

Cresswell, M.W.; Allen, R.A.; Linholm, L.W.; Guthrie, W.F.; Gurnell, A.W.; Microelectronic Test Structures, 1996. ICMTS 1996. Proceedings. 1996 IEEE

International Conference on , 25-28 March 1996

Pages:9 - 16

IEEE CNF [PDF Full-Text (380 KB)] [Abstract]

6 Analysis of the impact of proximity correction algorithms on circuit

performance

Li Chen; Milor, L.S.; Ouyang, C.H.; Maly, W.; Yeng-Kaung Peng;

Semiconductor Manufacturing, IEEE Transactions on, Volume: 12, Issue: 3, Aug.

Pages:313 - 322

IEEE JNL [PDF Full-Text (284 KB)] [Abstract]

# 7 A three-step method for the de-embedding of high-frequency Sparameter measurements

Cho, H.; Burk, D.E.;

Electron Devices, IEEE Transactions on , Volume: 38 , Issue: 6 , June 1991 Pages:1371 - 1375

# [Abstract] [PDF Full-Text (444 KB)] IEEE JNL

8 Production use of an integrated automatic defect classification (ADC) system operating in a laser confocal/white light imaging defect review

Advanced Semiconductor Manufacturing Conference and Workshop, 1996. ASMC 96 Proceedings, IEEE/SEMI 1996, 12-14 Nov. 1996 Li, J.; McIntyre, M.; Lee, K.; Worster, B.; Pages:107 - 111

# [Abstract] [PDF Full-Text (452 KB)] IEEE CNF

9 Removal of cable and connector dispersion in time-domain waveform measurements on 40 Gb integrated circuits

Scott, J.; Behnia, B.; Bossche, M.V.; Cognata, A.; Verspecht, J.; Verbeyst, F.; Thorn, M.; Scherrer, D.R.;

Microwave Symposium Digest, 2002 IEEE MTT-S International, Volume: 3, 2-7 June 2002

Pages:1669 - 1672

# [Abstract] [PDF Full-Text (487 KB)] IEEE CNF

# 10 An on-wafer fabricated free-chlorine sensor

van den Berg, A.; Koudelka-Hep, M.; van der Schoot, B.K.; Verney-Norberg, E.; Krebs, P.; Grisel, A.; de Rooij, N.F.;

Solid-State Sensors and Actuators, 1991. Digest of Technical Papers, TRANSDUCERS '91., 1991 International Conference on , 24-27 June 1991 Pages:233 - 236

# [Abstract] [PDF Full-Text (448 KB)] IEEE CNF

# 11 Junction-isolated electrical test structures for critical dimension calibration standards

Allen, R.A.; Cresswell, M.W.; Linholm, L.W.;

Semiconductor Manufacturing, IEEE Transactions on , Volume: 17, Issue: 2, May

2004

Pages: 79 - 83

IEEE JNL [PDF Full-Text (208 KB)] [Abstract] 12 DC-SQUIDs fabricated by electron beam direct writing

Carelli, P.; Foglietti, V.; Leoni, R.;

Magnetics, IEEE Transactions on , Volume: 23 , Issue: 2 , Mar 1987

Pages:1087 - 1089

[PDF Full-Text (560 KB)] IEEE JNL [Abstract]

removal of interconnect dispersion and measurement instrument jitter 13 Enhanced on-wafer time-domain waveform measurement through

Scott, J.B.; Verspecht, J.; Behnia, B.; Vanden Bossche, M.; Cognata, A.; Verbeyst,

F.; Thorn, M.L.; Scherrer, D.R.;

Microwave Theory and Techniques, IEEE Transactions on, Volume: 50, Issue:

12, Dec. 2002

Pages:3022 - 3028

IEEE JNL [PDF Full-Text (581 KB)] [Abstract]

14 A microneedle-based glucose monitor: fabricated on a wafer-level using

in-device enzyme immobilization

TRANSDUCERS, Solid-State Sensors, Actuators and Microsystems, 12th Innational Zimmermann, S.; Fienbork, D.; Stoeber, B.; Flounders, A.W.; Liepmann, D.;

Conference on, 2003, Volume: 1, 8-12 June 2003 Pages:99 - 102 vol.1

IEEE CNF [PDF Full-Text (402 KB)] [Abstract] 15 Automated metrology qualification strategy [IC measurement]

Chain, E.E.;

Advanced Semiconductor Manufacturing Conference and Workshop, 1996. ASMC

96 Proceedings. IEEE/SEMI 1996, 12-14 Nov. 1996

Pages:337 - 342

[Abstract] [PDF Full-Text (712 KB)] IEEE CNF

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am Ende, B.A.; Cresswell, M.W.; Allen, R.A.; Headley, T.J.; Guthrie, W.F.; Linholm,

L.W.; Bogardus, E.H.; Murabito, C.E.; Microelectronic Test Structures, 2002. ICMTS 2002. Proceedings of the 2002 International Conference on , 8-11 April 2002

Pages:1 - 6

# IEEE CNF [PDF Full-Text (391 KB)] [Abstract]

# 17 Calibration technique for MEMS membrane type strain sensors

University/Government/Industry Microelectronics Symposium, 1999. Proceedings of Li Cao; Tae Song Kim; Jia Zhou; Mantell, S.C.; Polla, D.L.; the Thirteenth Biennial, 20-23 June 1999 Pages:204 - 210

IEEE CNF [PDF Full-Text (356 KB)] [Abstract] Print Formst

Volklein, F.; Kessler, E.; Thermoelectrics, 1998. Proceedings ICT 98. XVII International Conference on , May

18 Thermoelectric microsensor for heat flux measurement

24-28, 1998

24-26, 1996 Pages:214 - 217 [Abstract] [PDF Full-Text (280 KB)] IEEE CNF

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